

P4C188/P4C188L ULTRA HIGH SPEED 16K x 4 STATIC CMOS RAMS



FEATURES

- Full CMOS, 6T Cell
- High Speed (Equal Access and Cycle Times)
 - 10/12/15/20/25 ns (Commercial)
 - 12/15/20/25/35 (Industrial)
 - 15/20/25/35/45 ns (Military)
- Low Power (Commercial/Military)
 - 715 mW Active - 12/15
 - 550/660 mW Active - 20/25/35/45
 - 193/220 mW Standby (TTL Input)
 - 83/110 mW Standby (CMOS Input) P4C188
 - 15 mW Standby (CMOS Input) (P4C188L Military)
- Single 5V±10% Power Supply
- Data Retention with 2.0V Supply (P4C188L Military)
- Three-State Outputs
- TTL/CMOS Compatible Outputs
- Fully TTL Compatible Inputs
- Standard Pinout (JEDEC Approved)
 - 22-Pin 300 mil DIP
 - 24-Pin 300 mil SOJ
 - 22-Pin 290 x 490 mil LCC



DESCRIPTION

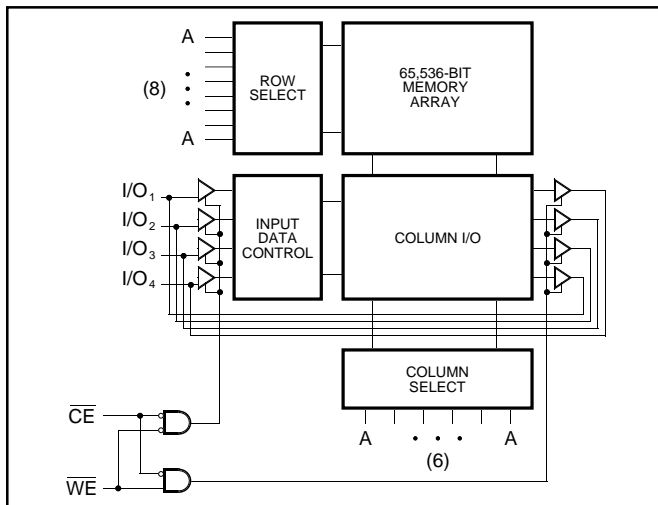
The P4C188 and P4C188L are 65,536-bit ultra high speed static RAMs organized as 16K x 4. The CMOS memories require no clocks or refreshing and have equal access and cycle times. Inputs and outputs are fully TTL-compatible. The RAMs operate from a single 5V±10% tolerance power supply. With battery backup, data integrity is maintained for supply voltages down to 2.0V. Current drain is typically 10 µA from a 2.0V supply.

Access times as fast as 12 nanoseconds are available, permitting greatly enhanced system speeds. CMOS is utilized to reduce power consumption to a low 715mW active, 193mW standby and only 5mW in the P4C188L version.

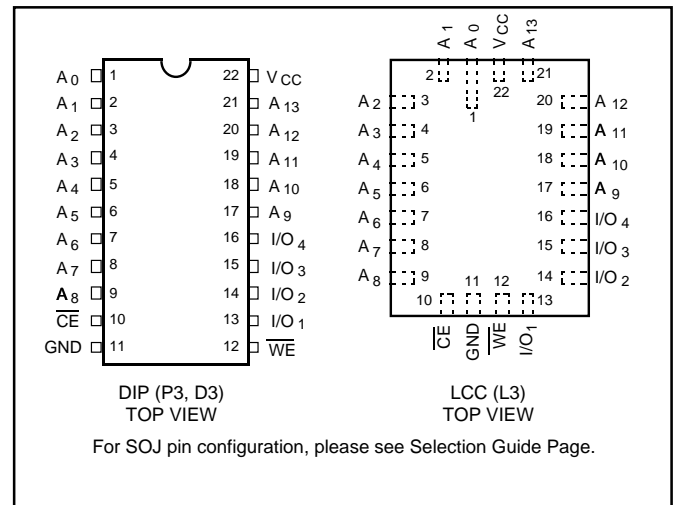
The P4C188 and P4C188L are available in 22-pin 300 mil DIP, 24-pin 300 mil SOJ and 22-pin LCC packages providing excellent board level densities.



FUNCTIONAL BLOCK DIAGRAM



PIN CONFIGURATIONS



Means Quality, Service and Speed

MAXIMUM RATINGS⁽¹⁾

| Symbol | Parameter | Value | Unit |
|-------------------|---|------------------------------|------|
| V _{CC} | Power Supply Pin with Respect to GND | -0.5 to +7 | V |
| V _{TERM} | Terminal Voltage with Respect to GND (up to 7.0V) | -0.5 to V _{CC} +0.5 | V |
| T _A | Operating Temperature | -55 to +125 | °C |

| Symbol | Parameter | Value | Unit |
|-------------------|------------------------|-------------|------|
| T _{BIAS} | Temperature Under Bias | -55 to +125 | °C |
| T _{STG} | Storage Temperature | -65 to +150 | °C |
| P _T | Power Dissipation | 1.0 | W |
| I _{OUT} | DC Output Current | 50 | mA |

RECOMMENDED OPERATING TEMPERATURE AND SUPPLY VOLTAGE

| Grade(2) | Ambient Temperature | GND | V _{CC} |
|------------|---------------------|-----|-----------------|
| Military | -55°C to +125°C | 0V | 5.0V ± 10% |
| Industrial | -40°C to +85°C | 0V | 5.0V ± 10% |
| Commercial | 0°C to +70°C | 0V | 5.0V ± 10% |

CAPACITANCES⁽⁴⁾

V_{CC} = 5.0V, T_A = 25°C, f = 1.0MHz

| Symbol | Parameter | Conditions | Typ. | Unit |
|------------------|--------------------|-----------------------|------|------|
| C _{IN} | Input Capacitance | V _{IN} = 0V | 5 | pF |
| C _{OUT} | Output Capacitance | V _{OUT} = 0V | 7 | pF |

DC ELECTRICAL CHARACTERISTICS

Over recommended operating temperature and supply voltage⁽²⁾

| Symbol | Parameter | Test Conditions | P4C188 | | P4C188L | | Unit |
|------------------|--|--|----------------------|----------------------|----------------------|----------------------|------|
| | | | Min | Max | Min | Max | |
| V _{IH} | Input High Voltage | | 2.2 | V _{CC} +0.5 | 2.2 | V _{CC} +0.5 | V |
| V _{IL} | Input Low Voltage | | -0.5 ⁽³⁾ | 0.8 | -0.5 ⁽³⁾ | 0.8 | V |
| V _{HC} | CMOS Input High Voltage | | V _{CC} -0.2 | V _{CC} +0.5 | V _{CC} -0.2 | V _{CC} +0.5 | V |
| V _{LC} | CMOS Input Low Voltage | | -0.5 ⁽³⁾ | 0.2 | -0.5(3) | 0.2 | V |
| V _{CD} | Input Clamp Diode Voltage | V _{CC} = Min., I _{IN} = 18 mA | | -1.2 | | -1.2 | V |
| V _{OL} | Output Low Voltage (TTL Load) | I _{OL} = +8 mA, V _{CC} = Min. | | 0.4 | | 0.4 | V |
| V _{OH} | Output High Voltage (TTL Load) | I _{OH} = -4 mA, V _{CC} = Min. | 2.4 | | 2.4 | | V |
| I _{LI} | Input Leakage Current | V _{CC} = Max. Mil. V _{IN} = GND to V _{CC} Com'l. | -10 -5 | +10 +5 | -5 n/a | +5 n/a | µA |
| I _{LO} | Output Leakage Current | V _{CC} = Max., $\overline{CE} = V_{IH}$ Mil. V _{OUT} = GND to V _{CC} Com'l. | -10 -5 | +10 +5 | -5 n/a | +5 n/a | µA |
| I _{SB} | Standby Power Supply Current (TTL Input Levels) | $\overline{CE} \geq V_{IH}$ Mil. V _{CC} = Max., Ind./Com'l. f = Max., Outputs Open | — — | 40 35 | — — | 40 n/a | mA |
| I _{SB1} | Standby Power Supply Current (CMOS Input Levels) | $\overline{CE} \geq V_{HC}$ Mil. V _{CC} = Max., Ind./Com'l. f = 0, Outputs Open V _{IN} ≤ V _{LC} or V _{IN} ≥ V _{HC} | — — | 20 15 | — — | 2.7 n/a | mA |

n/a = Not Applicable

Notes:

1. Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to MAXIMUM rating conditions for extended periods may affect reliability.
2. Extended temperature operation guaranteed with 400 linear feet per minute of air flow.
3. Transient inputs with V_{IL} and I_{IL} not more negative than -3.0V and -100mA, respectively, are permissible for pulse widths up to 20ns.
4. This parameter is sampled and not 100% tested.

POWER DISSIPATION CHARACTERISTICS VS. SPEED

| Symbol | Parameter | Temperature Range | -10 | -12 | -15 | -20 | -25 | -35 | -45 | Unit |
|----------|----------------------------|-------------------|-----|-----|-----|-----|-----|-----|-----|------|
| | | | | | | | | | | |
| I_{CC} | Dynamic Operating Current* | Commercial | 180 | 170 | 160 | 155 | 150 | N/A | N/A | mA |
| | | Industrial | N/A | 180 | 170 | 160 | 155 | 150 | N/A | mA |
| | | Military | N/A | N/A | 170 | 160 | 155 | 150 | 145 | mA |

* $V_{CC} = 5.5V$. Tested with outputs open. $f = \text{Max}$. Switching inputs are 0V and 3V. $\overline{CE} = V_{IL}$

DATA RETENTION CHARACTERISTICS (P4C188L Military Temperature Only)

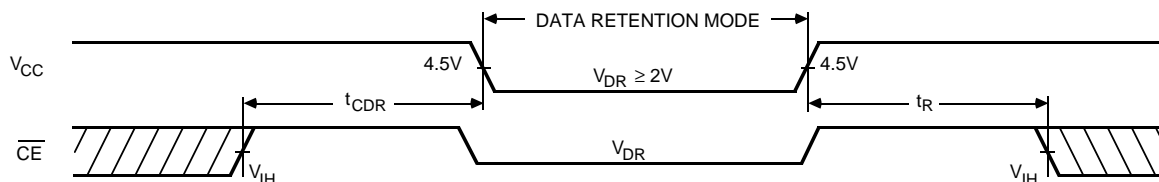
| Symbol | Parameter | Test Conditions | Min | Typ.* | | Max | | Unit |
|---------------|--------------------------------------|--|-------------|-----------------|-----------------|-----------------|-----------------|---------|
| | | | | $V_{CC} = 2.0V$ | $V_{CC} = 3.0V$ | $V_{CC} = 2.0V$ | $V_{CC} = 3.0V$ | |
| V_{DR} | V_{CC} for Data Retention | | 2.0 | | | | | V |
| I_{CCDR} | Data Retention Current | $\overline{CE} \geq V_{CC} - 0.2V$, $V_{IN} \geq V_{CC} - 0.2V$ or $V_{IN} \leq 0.2V$ | | 10 | 15 | 600 | 900 | μA |
| t_{CDR} | Chip Deselect to Data Retention Time | | 0 | | | | | ns |
| t_R^\dagger | Operation Recovery Time | | t_{RC}^\S | | | | | ns |

* $T_A = +125^\circ C$

$^\S t_{RC}$ = Read Cycle Time

† This parameter is guaranteed but not tested.

DATA RETENTION WAVEFORM

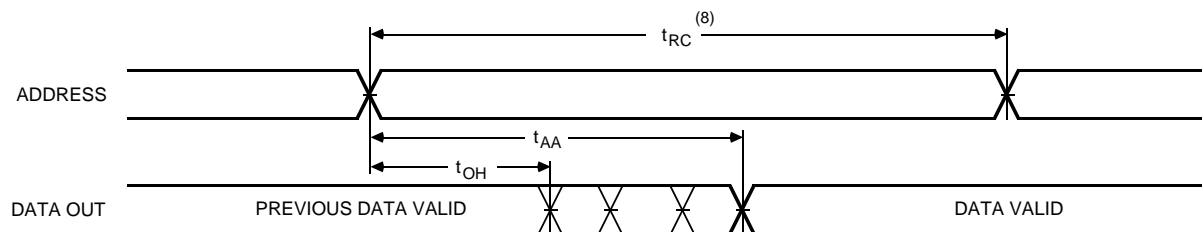


AC CHARACTERISTICS—READ CYCLE

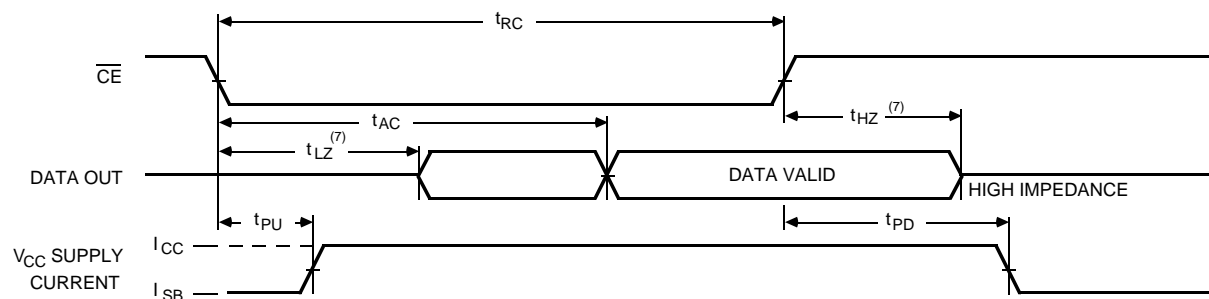
($V_{CC} = 5V \pm 10\%$, All Temperature Ranges)⁽²⁾

| Sym. | Parameter | -10 | | -12 | | -15 | | -20 | | -25 | | -35 | | -45 | | Unit |
|----------|----------------------------------|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|------|
| | | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | |
| t_{RC} | Read Cycle Time | 10 | | 12 | | 15 | | 20 | | 25 | | 35 | | 45 | | ns |
| t_{AA} | Address Access Time | | 10 | | 12 | | 15 | | 20 | | 25 | | 35 | | 45 | ns |
| t_{AC} | Chip Enable Access Time | | 10 | | 12 | | 15 | | 20 | | 25 | | 35 | | 45 | ns |
| t_{OH} | Output Hold from Address Change | 2 | | 2 | | 2 | | 2 | | 2 | | 2 | | 2 | | ns |
| t_{LZ} | Chip Enable to Output in Low Z | 2 | | 2 | | 2 | | 3 | | 3 | | 3 | | 3 | | ns |
| t_{HZ} | Chip Disable to Output in High Z | | 5 | | 6 | | 6 | | 8 | | 10 | | 20 | | 25 | ns |
| t_{PU} | Chip Enable to Power Up Time | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | ns |
| t_{PD} | Chip Disable to Power Down Time | | 10 | | 12 | | 15 | | 20 | | 25 | | 35 | | 45 | ns |

TIMING WAVEFORM OF READ CYCLE NO. 1⁽⁵⁾



TIMING WAVEFORM OF READ CYCLE NO. 2⁽⁶⁾



Notes:

5. \overline{CE} is LOW and \overline{WE} is HIGH for READ cycle.
 6. \overline{WE} is HIGH, and address must be valid prior to or coincident with \overline{CE} transition LOW.

7. Transition is measured $\pm 200\text{mV}$ from steady state voltage prior to change with specified loading in Figure 1. This parameter is sampled and not 100% tested.

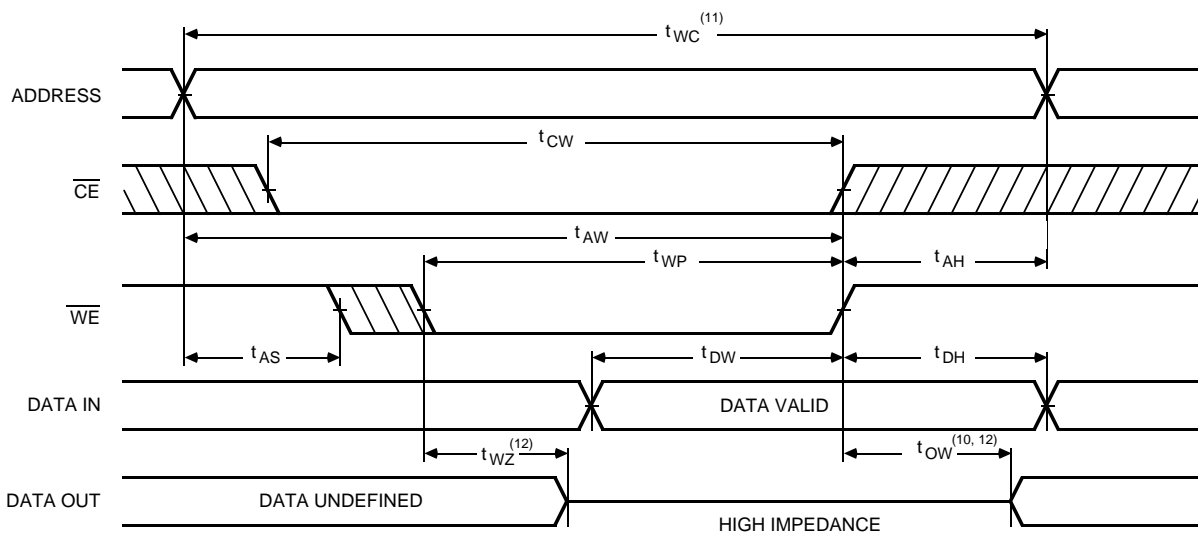
8. Read Cycle Time is measured from the last valid address to the first transitioning address.

AC CHARACTERISTICS - WRITE CYCLE

($V_{CC} = 5V \pm 10\%$, All Temperature Ranges)⁽²⁾

| Sym. | Parameter | -10 | | -12 | | -15 | | -20 | | -25 | | -35 | | -45 | | Unit |
|----------|-------------------------------------|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|-----|------|
| | | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | Min | Max | |
| t_{WC} | Write Cycle Time | 10 | | 12 | | 13 | | 20 | | 25 | | 35 | | 45 | | ns |
| t_{CW} | Chip Enable Time to End of Write | 7 | | 8 | | 10 | | 13 | | 15 | | 25 | | 35 | | ns |
| t_{AW} | Address Valid to End of Write | 7 | | 8 | | 10 | | 15 | | 20 | | 25 | | 35 | | ns |
| t_{AS} | Address Set-up Time | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | ns |
| t_{WP} | Write Pulse Width | 8 | | 9 | | 10 | | 13 | | 15 | | 25 | | 35 | | ns |
| t_{AH} | Address Hold Time from End of Write | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | ns |
| t_{DW} | Data Valid to End of Write | 5 | | 6 | | 7 | | 8 | | 10 | | 15 | | 20 | | ns |
| t_{DH} | Data Hold Time | 0 | | 0 | | 0 | | 0 | | 0 | | 0 | | 5 | | ns |
| t_{WZ} | Write Enable to Output in High Z | | 5 | | 6 | | 6 | | 8 | | 10 | | 15 | | 20 | ns |
| t_{DW} | Output Active from End of Write | 2 | | 2 | | 2 | | 2 | | 2 | | 3 | | 3 | | ns |

TIMING WAVEFORM OF WRITE CYCLE NO. 1 (\overline{WE} CONTROLLED)⁽⁹⁾

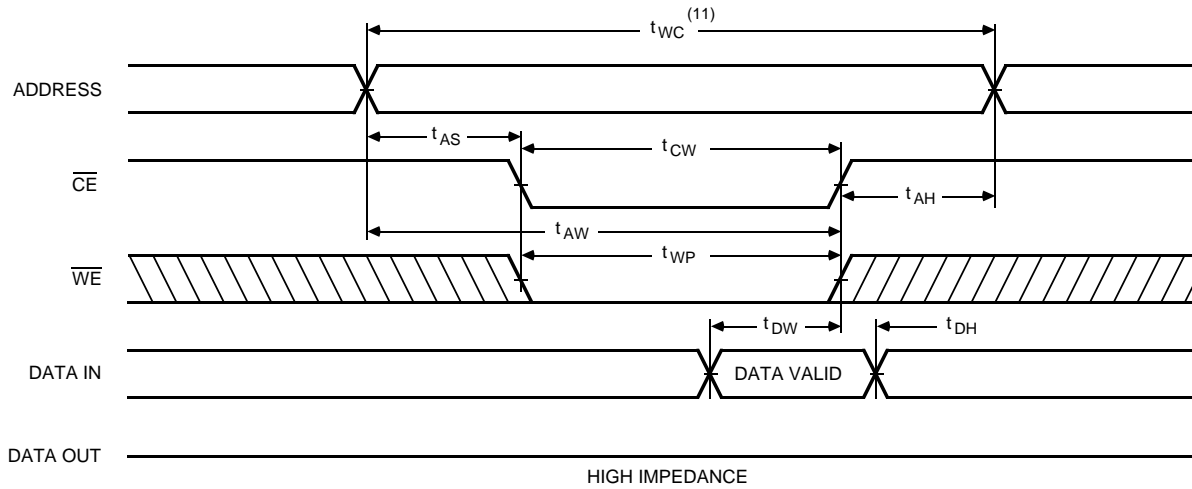


Notes:

- \overline{CE} and \overline{WE} must be LOW for WRITE cycle.
- If \overline{CE} goes HIGH simultaneously with \overline{WE} HIGH, the output remains in a high impedance state.
- Write Cycle Time is measured from the last valid address to the first transition address.

- Transition is measured $\pm 200\text{mV}$ from steady state voltage prior to change with specified loading in Figure 1. This parameter is sampled and not 100% tested.

TIMING WAVEFORM OF WRITE CYCLE NO. 2 (\overline{CE} CONTROLLED)⁽⁹⁾



AC TEST CONDITIONS

| | |
|-------------------------------|---------------------|
| Input Pulse Levels | GND to 3.0V |
| Input Rise and Fall Times | 3ns |
| Input Timing Reference Level | 1.5V |
| Output Timing Reference Level | 1.5V |
| Output Load | See Figures 1 and 2 |

TRUTH TABLE

| Mode | \overline{CE} | \overline{WE} | Output | Power |
|---------|-----------------|-----------------|------------------|---------|
| Standby | H | X | High Z | Standby |
| Read | L | H | D _{OUT} | Active |
| Write | L | L | D _{IN} | Active |

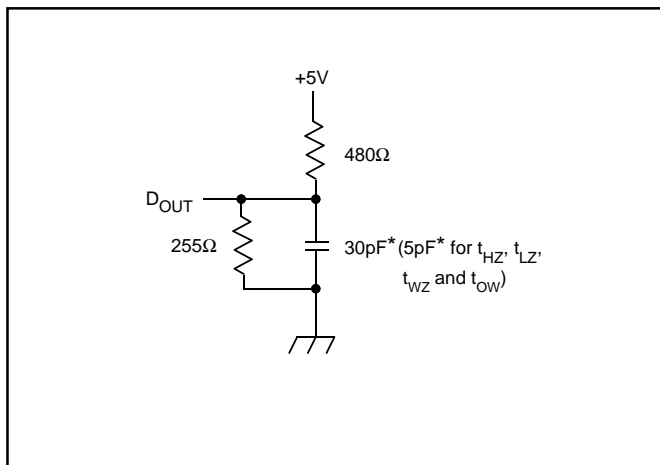


Figure 1. Output Load

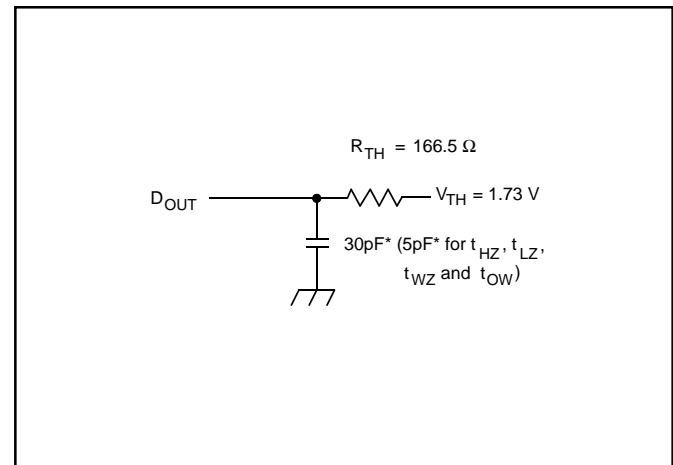


Figure 2. Thevenin Equivalent

* including scope and test fixture.

Note:

Because of the ultra-high speed of the P4C188/L, care must be taken when testing this device; an inadequate setup can cause a normal functioning part to be rejected as faulty. Long high-inductance leads that cause supply bounce must be avoided by bringing the V_{CC} and ground planes directly up to the contactor fingers. A 0.01 μF high frequency

capacitor is also required between V_{CC} and ground. To avoid signal reflections, proper termination must be used; for example, a 50Ω test environment should be terminated into a 50Ω load with 1.73V (Thevenin Voltage) at the comparator input, and a 116Ω resistor must be used in series with D_{OUT} to match 166Ω (Thevenin Resistance).

PACKAGE SUFFIX

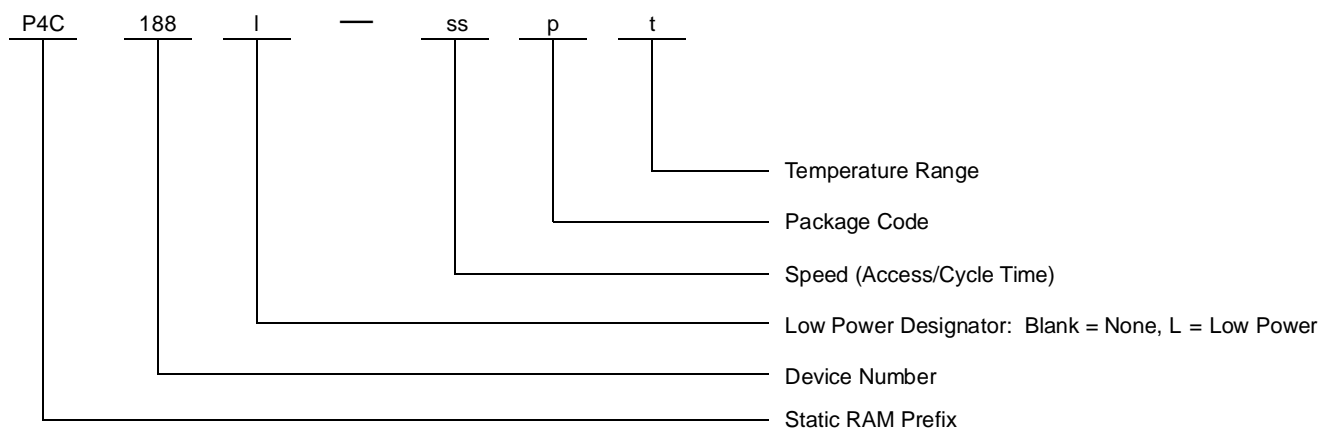
| Package Suffix | Description |
|----------------|------------------------------------|
| P | Plastic DIP, 300 mil wide standard |
| J | Plastic SOJ, 300 mil wide standard |
| L | Leadless Chip Carrier (ceramic) |
| D | CERDIP, 300 mil wide standard |

TEMPERATURE RANGE SUFFIX

| Temperature Range Suffix | Description |
|--------------------------|---|
| C | Commercial Temperature Range, 0°C to +70°C. |
| I | Industrial Temperature Range, -45°C to +85°C. |
| M | Military Temperature Range, -55°C to +125°C. |
| MB | Mil. Temp. with MIL-STD-883D Class B compliance |

ORDERING INFORMATION

The following part numbering scheme is used for the P4C188:



I = Ultra-low standby power designator L, if needed.

ss = Speed (access/cycle time in ns), e.g., 25, 35

p = Package code, i.e., P, J, D, L.

t = Temperature range, i.e., C, M, MB.

The P4C188 is also available per SMD 5962-89692 and 5962-86859

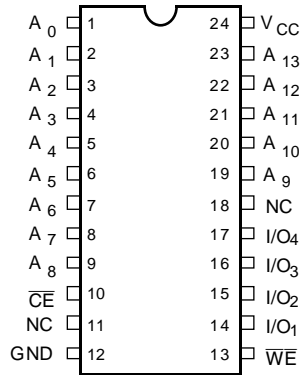
SELECTION GUIDE

The P4C188/L is available in the following temperature, speed and package options. The P4C188L is only available over the Military Temperature range.

| Temperature Range | Package | Speed (ns) | | | | | | |
|---------------------|-------------|------------|-------|--------|--------|--------|--------|--------|
| | | 10 | 12 | 15 | 20 | 25 | 35 | 45 |
| Commercial | Plastic DIP | -10PC | -12PC | -15PC | -20PC | -25PC | N/A | N/A |
| | Plastic SOJ | -10JC | -12JC | -15JC | -20JC | -25JC | N/A | N/A |
| Industrial | Plastic DIP | N/A | -12PI | -15PI | -20PI | -25PI | -35PI | N/A |
| | Plastic SOJ | N/A | -12JI | -15JI | -20JI | -25JI | -35JI | N/A |
| Military Temp. | CERDIP | N/A | N/A | -15DM | -20DM | -25DM | -35DM | -45DM |
| | LCC | N/A | N/A | -15LM | -20LM | -25LM | -35LM | -45LM |
| Military Processed* | CERDIP | N/A | N/A | -15DMB | -20DMB | -25DMB | -35DMB | -45DMB |
| | LCC | N/A | N/A | -15LMB | -20LMB | -25LMB | -35LMB | -45LMB |

* Military temperature range with MIL-STD-883, Class B processing.
N/A = Not available

SOJ PIN CONFIGURATION



SOJ (J4)
TOP VIEW